

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10594021	PELZER, HEIKO
	Examiner	Art Unit
	JENNIFER F CHANG	2821

SEARCHED

Class	Subclass	Date	Examiner
343	700MS	10/23/2008	Jennifer Chang

SEARCH NOTES

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INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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